

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Application Number : 10/553,470 Confirmation No.: 8935
: National Phase of International App'l. No. PCT/DE2004/000801
Applicant Ralf LERNER
Filed : May 19, 2006
Title : MONITORING THE REDUCTION OF THICKNESS AS
MATERIAL IS REMOVED FROM A WAFER COMPOSITE AND
TEST STRUCTURE FOR MONITORING REMOVAL OF
MATERIAL
TC/Art Unit : 2818
Examiner: : Lopez Esquerra, Andres
Docket No. : 60291.000041
Customer No. : 21967

Mail Stop: AF

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

NOTICE OF APPEAL

Sir:

Applicant hereby appeals to the Board of Patent Appeals and Interferences from the last decision of the Examiner rejecting claims 1-24 in the above-captioned application.

Please charge the undersigned's Deposit Account No. 50-0206 in the amount of \$540.00 to cover the Notice of Appeal fee. In the event of any variance between the amount enclosed and the fees determined by the U.S. Patent and Trademark Office, please charge or credit any such variance to the undersigned's Deposit Account No. 50-0206.

Respectfully submitted,
HUNTON & WILLIAMS LLP

Dated: March 17, 2009

By: 

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